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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/624,944	CHEN ET AL.	
Examiner	Art Unit	
Paul A. Wartalowicz	1754	

	SEAR	CHED	
Class	Subclass	Date	Examiner

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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EAST		3/5/2006	PW
Inventor		3/5/2006	PW